INFORMATION DISCLOSURE CITATION IN AN APPLICATION (PTO-1449)			FILING DATE August 1, 2003	O USA/ AMCS/APC ICANT ander T. SCHWARM et al. G DATE GROUP			
		U.	S. PATENT DO	CUMENTS			
EXAMINER'S INITIALS	PATENT NO.	DATE	N	IAME	CLASS	SUBCLASS	FILING DATE
	5,975,994	11/02/99	Sandhu et al.				06/11/97
	6,113,462	09/05/00	Yang				12/18/97
	6,230,069 B1	05/08/01	Campbell et al.				06/26/98
3	6,268,270 B1	07/31/01	Scheid et al.				10/29/99
	6,277,014 B1	08/21/01	Chen et al.				10/09/98
	6,291,367 B1	09/18/01	Kelkar				06/01/00
3	6,465,263 B1	10/15/02	Coss, Jr. et al.				01/04/00
0	6,532,555 B1	03/11/03	Miller et al.			1	10/29/99
3	6,535,783 B1	03/18/03	Miller et al.				03/05/01
	6,541,401 B1	04/01/03	Herner et al.	•			07/31/00
	6,546,508 B1	04/08/03	Sonderman et a	1.			10/29/99
3	6,556,881 B1	04/29/03	Miller				09/09/99
(2)	6,652,355 B2	11/25/03	Wiswesser et al				06/04/01
X	6,725,402 B1	04/20/04	Coss, Jr. et al.				07/31/00
		<u> </u>					
			 				
				· · · · · ·			
·		 		<u> </u>			
			-				
EXAMINER)	D	ATE CONSIDEREI	5		

	A. Cappelli, and K. C. Saraswa for Deposition of Silicon Diox Vol. 11, No. 3, pp. 720-726. 'Analytical Model for Chemica fract). Journal of Crystal Growing, C.L. Lee, C.H. Wu, S. Lin al-Time Equipment Monitoring logy Workshop, pp. 111-121. gration at AMD with Workstrophy of the June 18, 200 of 10/174,377, filed June 18, 200 of 10/174,377, fil	GROUP 2812 c.) t. May/June 1993. "Two ide from al Vapor Deposition of SiO ₂ wth, Vol. 140, Issues 3-4, pp. S.J. Huang, Y.C. Lee, S.G. g and Fault Detection cam." IEEE, pp. 325-327. 2. 1002. No. PCT/US02/19116.				
September 9, 2004. Written Opinion for PCT Se	August 25, 2004. Office Action for U.S. Serial No. 09/998,384, filed November 30, 2001. September 9, 2004. Written Opinion for PCT Serial No. PCT/US02/21942. September 16, 2004. International Preliminary Examination Report for PCT Serial No. PCT/US02/24859					
Syptemot 10, 2004. International Fronting 1	Authiniation Report for Text of					
EXAMINER	ATE CONSIDERED	5/05				

SHEET 1 OF 3

INFORMATION DISCLOSURE CITATION IN AN APPLICATION (PTO-1449)	ATTY. DOCKET NO. 007720 USA/ FPS/MMCS/APC APPLICANT	SERIAL NO. 10/632,107		
OE O LEGISLA	Alexander T. SCHWARM et al.			
REAL TRADELINITES	FILING DATE August 1, 2003	GROUP 2812		
OTHER ART (Including Author, Ti				
October 1, 2004. International Preliminary Exam	nination Report for PCT Serial	No. PCT/US03/23964.		
·				
·				
·				
EXAMINER	DATE CONSIDERED	16/05		

INFORMATION DISCLOSURE CITATION IN AN APPLICATION O P E CONTROLLED O T TOUR SET TRADESINGS TRADESINGS			SURE	ATTY. DOCKET NO. 007720 USA/ FPS/MMCS/APC APPLICANT Alexander T. SCHWAF FILING DATE August 1, 2003		SERIAL NO. 10/632,107 RM et al. GROUP 2812	
		1	U.S. PATENT D	OCUMENTS		٠,٠	
EXAMINER'S INITIALS	PATENT NO.	DATE		NAME	CLASS	SUBCLASS	FILING DATE
	6,381,564 B1	04/30/02	David et al.			<u> </u>	05/03/99
0	2002/0183986 A1	12/05/02	Stewart et al.				05/30/01
9	2003/0154062 A1	08/14/03	Daft et al.				10/15/01
5	6,529,789 B1	03/04/03	Campbell et al.			<u> </u>	03/14/02
	* *						
					L		
			·			1	
					-	_	
		<u> </u>			<u> </u>		
	<u> </u>	 					1
	·			·		<u> </u>	<u> </u>
			 			 	
	 	-			-	+	
·					 		
EXAMINER			·	DATE CONSIDERE	D /	<u></u>	1
	1			a	7 ~	lat	

SHEET 3 OF 3

INFORMATION DISCLOSURE CITATION IN AN OUTPEARPLICATION	ATTY. DOCKET NO. 007720 USA/ FPS/MMCS/APC	SERIAL NO. 10/632,107				
DEL D 7. 2004. (S) TO-1449)	APPLICANT Alexander T. SCHWARM et al.					
	FILING DATE August 1, 2003	GROUP 2812				
OTHER ART (Including Author	, Title, Date, Pertinent Pages,	Etc.)				
September 29, 2004. Office Action for U.S. S	September 29, 2004. Office Action for U.S. Serial No. 09/363,966, filed July 29, 1999.					
October 1, 2004. International Preliminary E	October 1, 2004. International Preliminary Examination Report for PCT Serial No. PCT/US03/23964.					
October 6, 2004. Office Action for U.S. Series	October 6, 2004. Office Action for U.S. Serial No. 10/759,108, filed January 20, 2004.					
October 12, 2004. International Preliminary	October 12, 2004. International Preliminary Examination Report for PCT Serial No. PCT/US02/19061.					
November 17, 2004. Written Opinion for PC	November 17, 2004. Written Opinion for PCT Serial No. PCT/US01/27407.					
	·					
EXAMINER	DATE CONSIDERED	5/8/05				

1